

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/533,698	PILOTEK ET AL.	
		Examiner	Art Unit	Page 1 of 1
		John Freeman	4174	

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,597,250 A	08-1971		106/418
*	B	US-3,647,492 A	03-1972	Chapman et al.	106/418
*	C	US-4,856,857 A	08-1989	Takeuchi et al.	359/3
*	D	US-5,035,473 A	07-1991	Kuwayama et al.	359/13
*	E	US-6,112,388 A	09-2000	Kimoto et al.	29/17.3
*	F	US-6,157,489 A	12-2000	Bradley et al.	359/584
*	G	US-6,398,999 B1	06-2002	Josephy et al.	264/81
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Petermann, J. "Epitaxial Crystallization of Polymers and Metals on Highly Oriented Thin Polymer Films."□□Physica Scripta. Vol T49, 256-259, 1993.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.